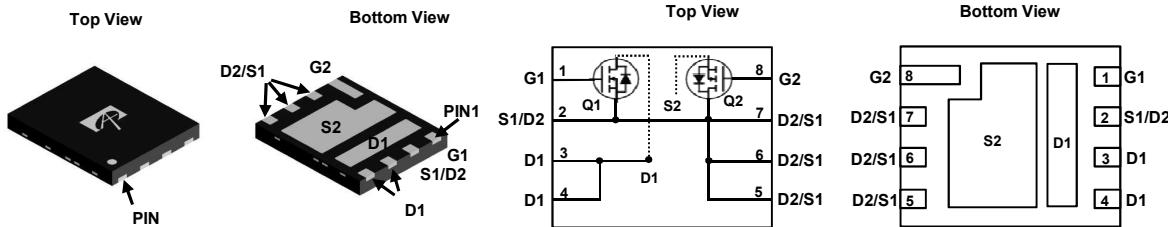


General Description		Product Summary	
• Bottom Source Technology		<u>Q1</u>	<u>Q2</u>
• Very Low $R_{DS(ON)}$		V _{DS} 30V	30V
• Low Gate Charge		I _D (at V _{GS} =10V) 55A	85A
• High Current Capability		R _{DS(ON)} (at V _{GS} =10V) < 5mΩ	< 1.4mΩ
• RoHS and Halogen-Free Compliant		R _{DS(ON)} (at V _{GS} =4.5V) < 8mΩ	< 1.8mΩ
Applications		100% UIS Tested 100% R _g Tested	
<ul style="list-style-type: none"> DC/DC Converters in Computing, Servers, and POL Non-Isolated DC/DC Converters in Telecom and Industrial 		 Green Product	

DFN 5x6E


Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOE6932	DFN 5x6E	Tape & Reel	3000

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter	Symbol	Max Q1	Max Q2	Units
Drain-Source Voltage	V _{DS}	30	30	V
Gate-Source Voltage	V _{GS}	±20	±12	V
Continuous Drain Current ^G	I _D	55	85	A
		35	85	
Pulsed Drain Current ^C	I _{DM}	120	340	
Continuous Drain Current ^C	I _{DSM}	21	38	A
		16	30	
Avalanche Current ^C	I _{AS}	60	80	A
Avalanche energy ^C	E _{AS}	18	32	mJ
V _{DS} Spike	10μs	V _{SPIKE}	36	V
Power Dissipation ^B	P _D	24	52	W
		9.6	20	
Power Dissipation ^A	P _{DSM}	3.5	3.5	W
		2.2	2.2	
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ Q1	Typ Q2	Max Q1	Max Q2	Units	
Maximum Junction-to-Ambient ^A	t ≤ 10s	R _{θJA}	25	25	35	°C/W	
Maximum Junction-to-Ambient ^{A,D}	Steady-State	R _{θJA}	50	50	65	°C/W	
Maximum Junction-to-Case (Note)	Steady-State	R _{θJC}	4	1.8	5.2	2.4	°C/W

Note: Bottom S2, D1.

Q1 Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{VGS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $\text{T}_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 20\text{V}$			± 100	nA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.3	1.7	2.2	V
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $\text{T}_J=125^\circ\text{C}$		3.5	5	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		5	7	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		57		S
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.7	1	V
I_{S}	Maximum Body-Diode Continuous Current				30	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		1150		pF
C_{oss}	Output Capacitance			380		pF
C_{rss}	Reverse Transfer Capacitance			55		pF
R_{g}	Gate resistance	$\text{f}=1\text{MHz}$	0.6	1.2	2.0	Ω
SWITCHING PARAMETERS						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		16	25	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			7.5	15	nC
Q_{gs}	Gate Source Charge			2.5		nC
Q_{gd}	Gate Drain Charge			3.0		nC
Q_{gs}	Gate Source Charge			2.5		nC
Q_{gd}	Gate Drain Charge	$\text{V}_{\text{GS}}=4.5\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		3.0		nC
$\text{t}_{\text{D}(\text{on})}$	Turn-On Delay Time			6.5		ns
t_{r}	Turn-On Rise Time			4.5		ns
$\text{t}_{\text{D}(\text{off})}$	Turn-Off Delay Time			19		ns
t_{f}	Turn-Off Fall Time			3		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		11.5		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		20		nC

A. The value of R_{BJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{BJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$.

D. The R_{BJA} is the sum of the thermal impedance from junction to case R_{BJC} and case to ambient.

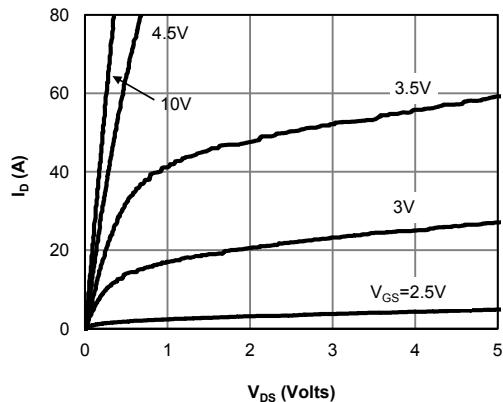
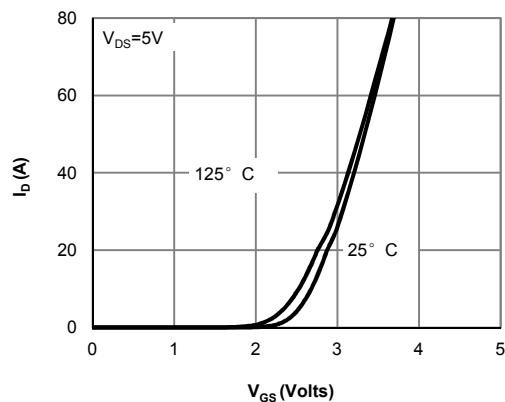
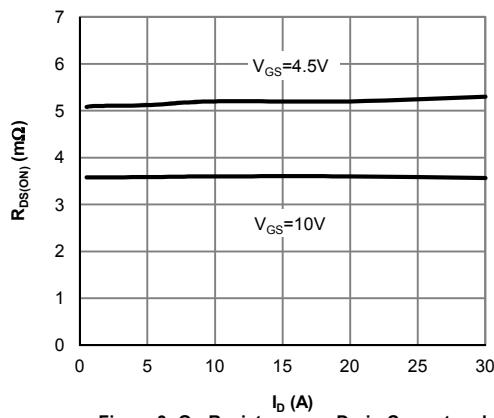
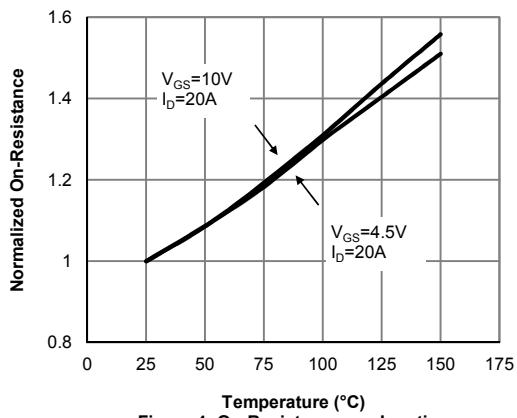
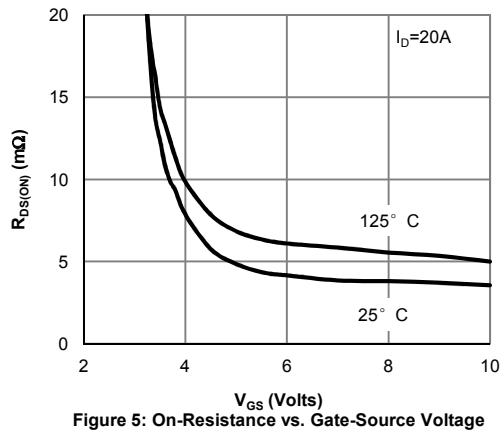
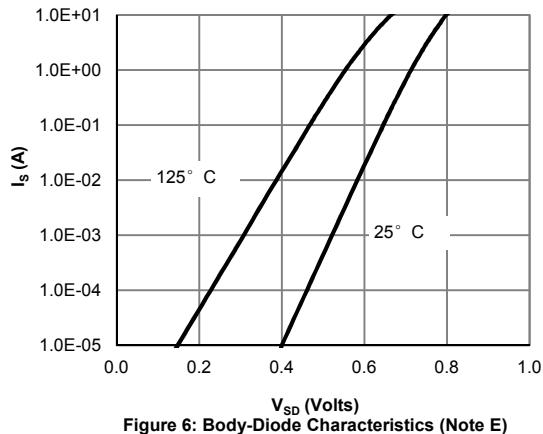
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

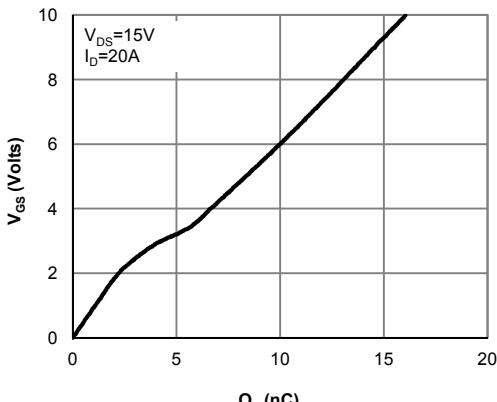
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

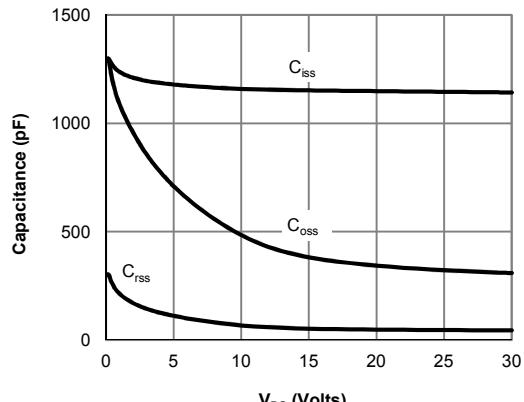


Figure 8: Capacitance Characteristics

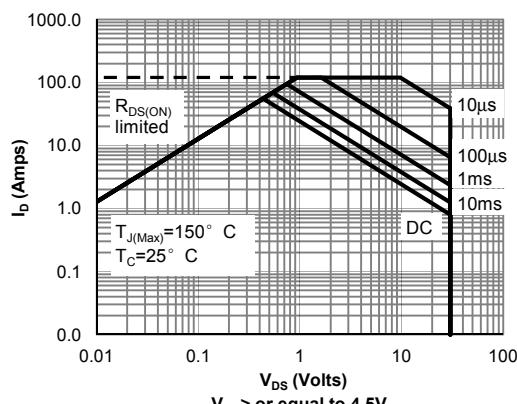


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

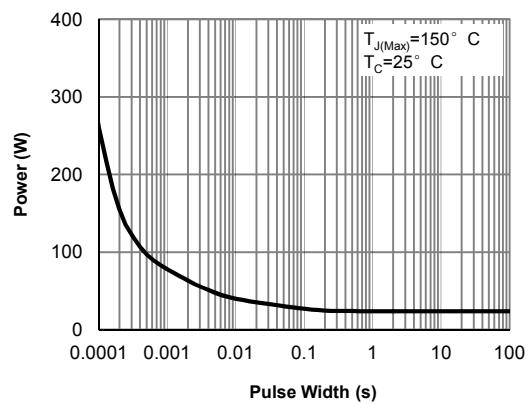
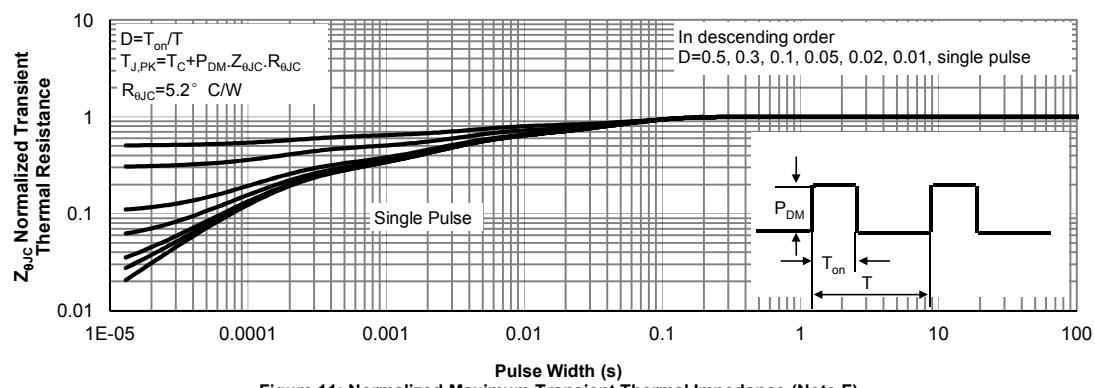


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)



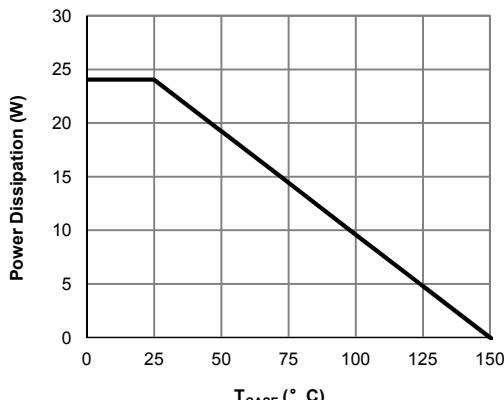
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

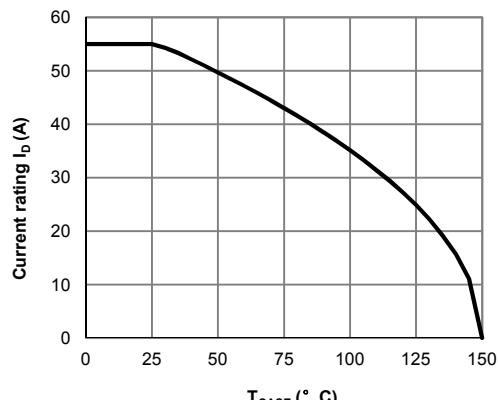


Figure 13: Current De-rating (Note F)

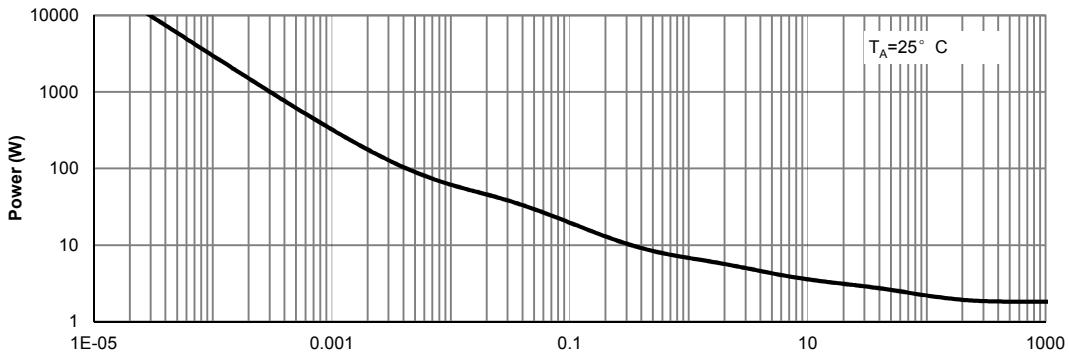


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

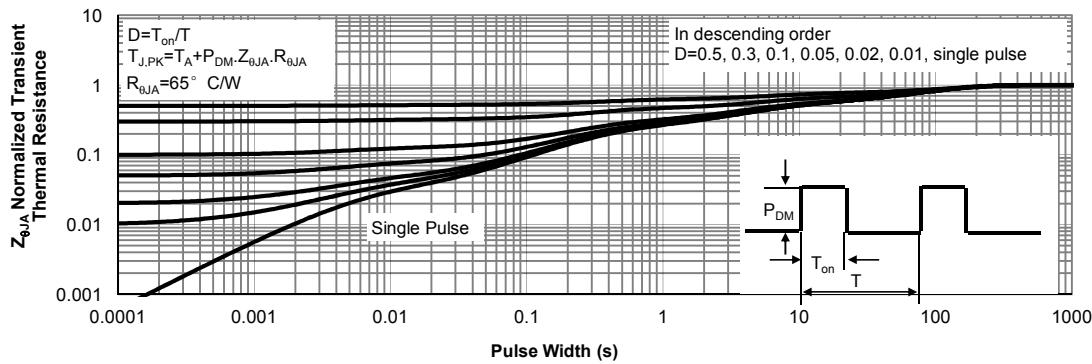


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Q2 Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{V}_{\text{GS}}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$		1		μA
			$T_J=55^\circ\text{C}$		5	
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 12\text{V}$			± 100	nA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.2	1.5	1.9	V
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$		0.9	1.4	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		1.45	2.2	
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		1.15	1.8	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		200		S
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.7	1	V
I_{S}	Maximum Body-Diode Continuous Current				60	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		4180		pF
C_{oss}	Output Capacitance			880		pF
C_{rss}	Reverse Transfer Capacitance			125		pF
R_{g}	Gate resistance	$\text{f}=1\text{MHz}$	0.6	1.3	2.2	Ω
SWITCHING PARAMETERS						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		65	100	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			30	50	nC
Q_{gs}	Gate Source Charge			9.5		nC
Q_{gd}	Gate Drain Charge			7		nC
Q_{gs}	Gate Source Charge			9.5		nC
Q_{gd}	Gate Drain Charge	$\text{V}_{\text{GS}}=4.5\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		7		nC
$t_{\text{D}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		9		ns
t_{r}	Turn-On Rise Time			8		ns
$t_{\text{D}(\text{off})}$	Turn-Off Delay Time			50.5		ns
t_{f}	Turn-Off Fall Time			8.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		17		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		42		nC

A. The value of R_{BJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{BJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.

D. The R_{BJA} is the sum of the thermal impedance from junction to case R_{BJC} and case to ambient.

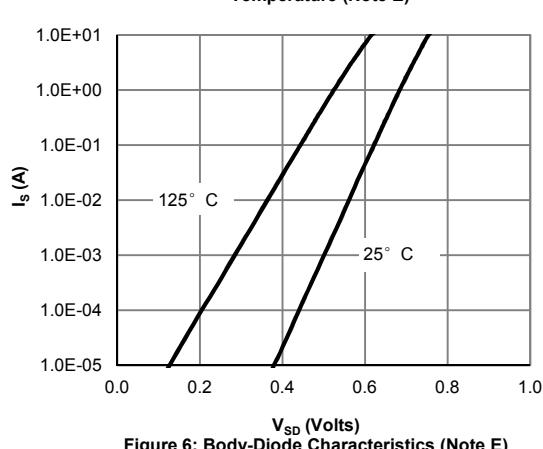
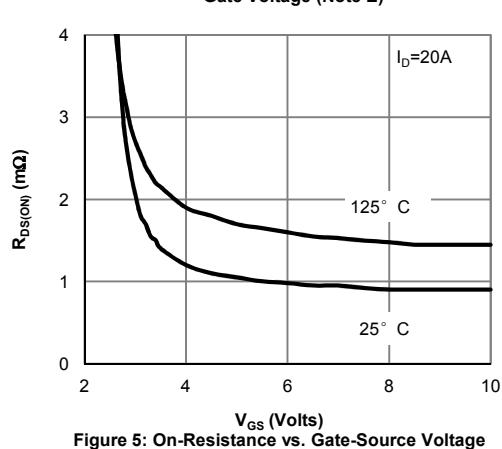
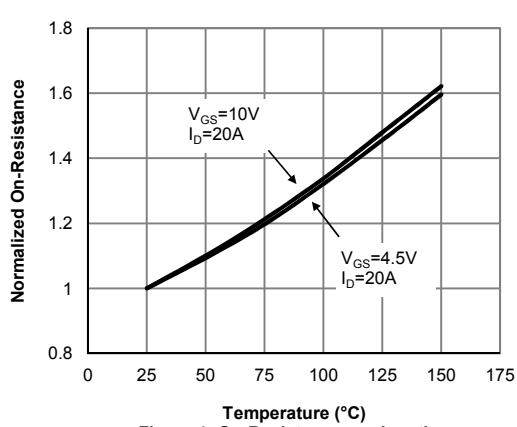
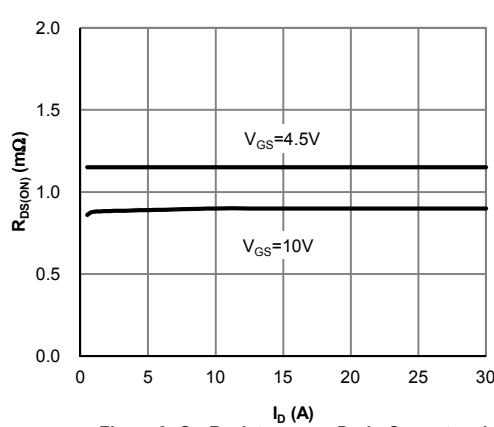
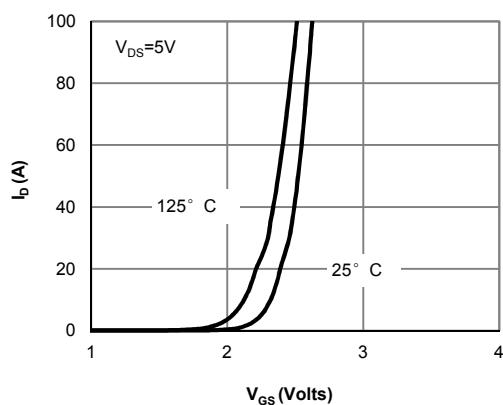
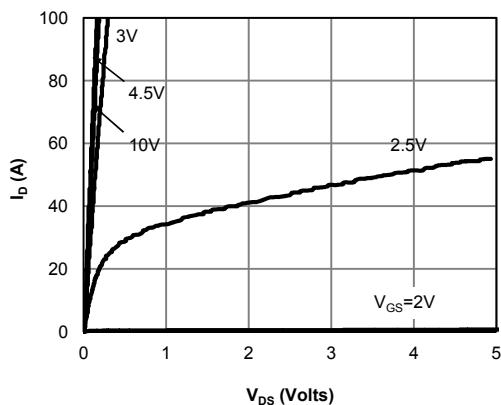
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


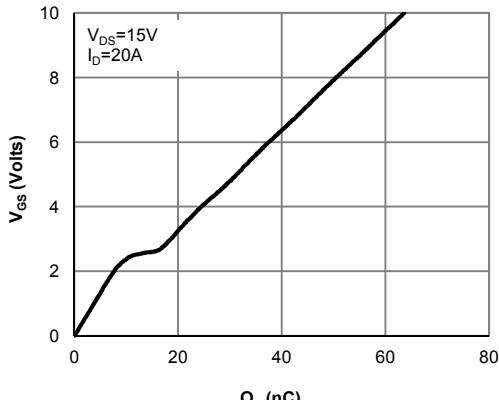
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

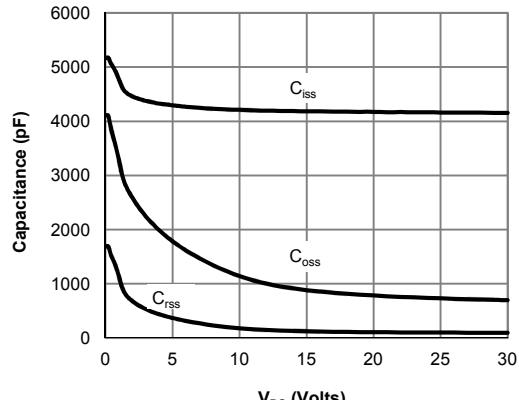


Figure 8: Capacitance Characteristics

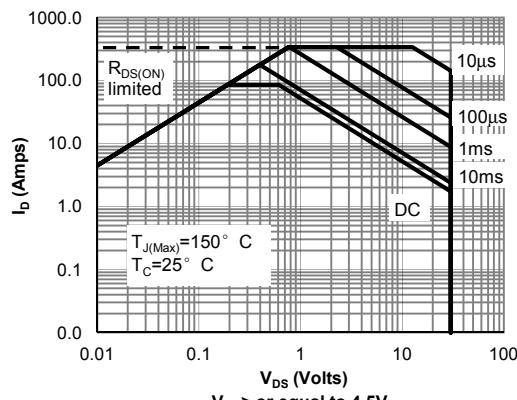


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

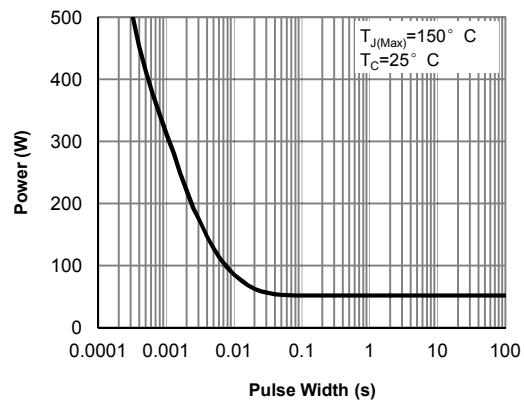


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

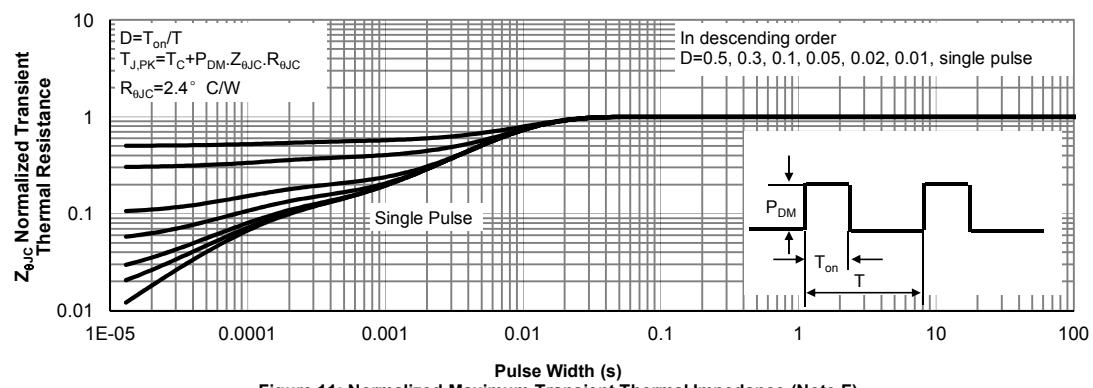


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

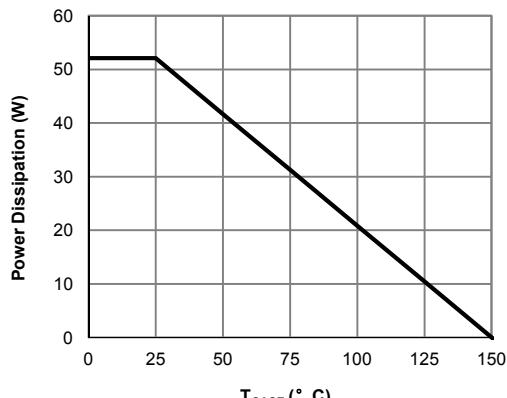
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

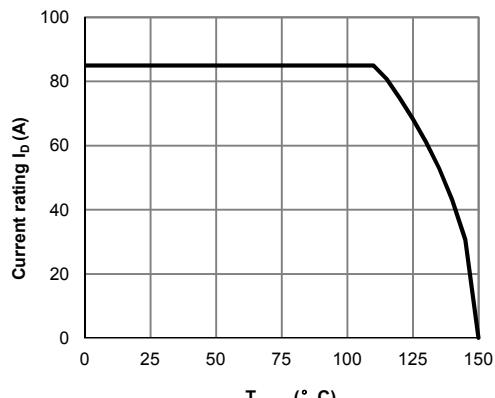


Figure 13: Current De-rating (Note F)

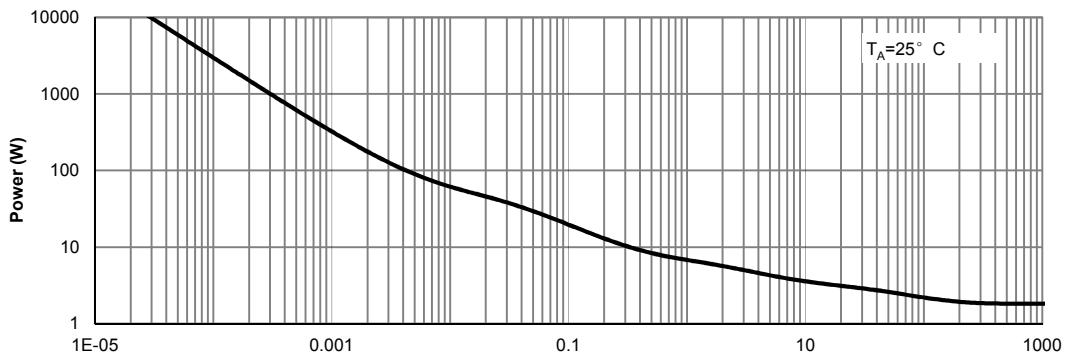


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

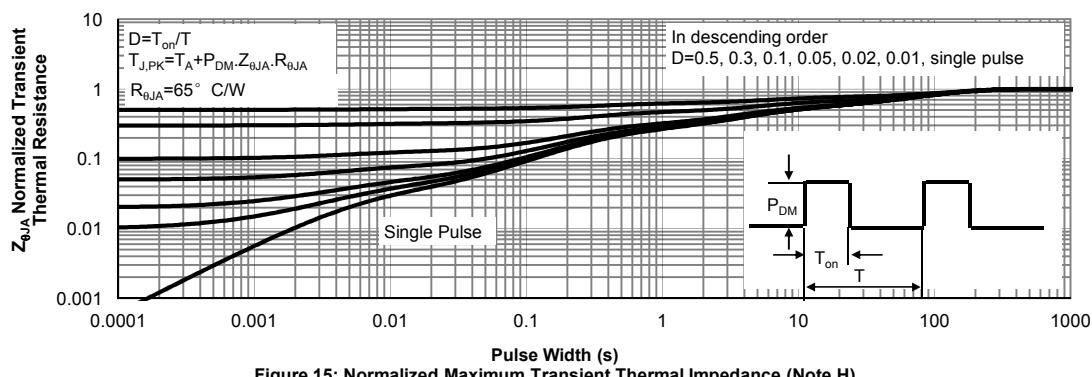


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

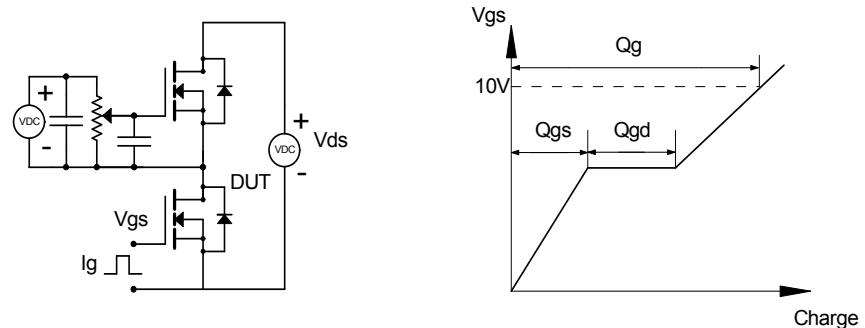


Figure B: Resistive Switching Test Circuit & Waveforms

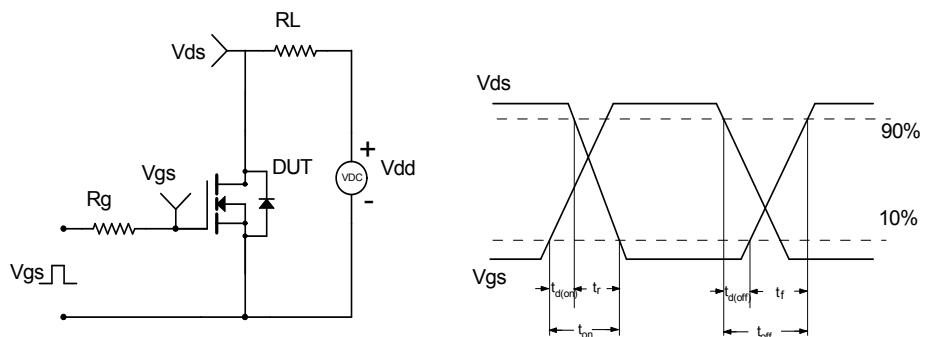


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

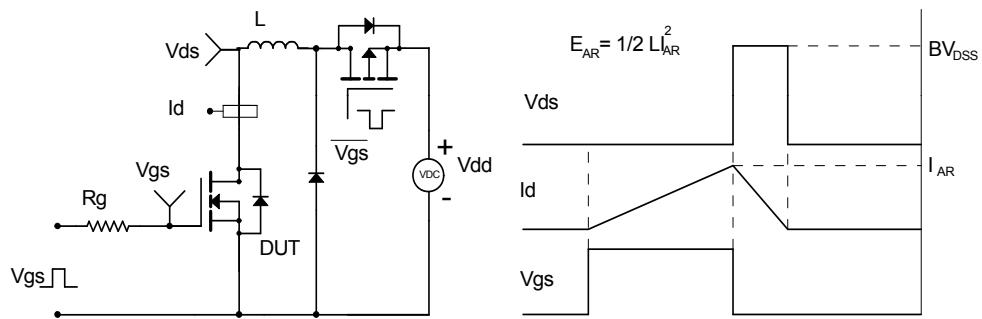


Figure D: Diode Recovery Test Circuit & Waveforms

